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Sixth Symposium Optics in Industry

**Julio C. Gutiérrez-Vega
Josué Dávila-Rodríguez
Carlos López-Mariscal**
Editors

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Introduction

This sixth symposium on Optics in Industry has continued the effort to document ongoing work on the various facets of theory and applications of optics in industry in México. This year's conference was a two-day event.

Sixty-seven technical papers were presented, divided into fourteen topics. We believe that this division largely reflects the increasing trends and the wide applicability of optics in industrial applications. Papers from México, Canada, USA, Colombia, Peru, Spain, and Kuwait were presented.

The success of this meeting was to a great extent due to the help of the Photonics and Mathematical Optics Group at Tecnológico de Monterrey México, the SPIE Student Chapter at the same university, and the administrative staff of the Mexican Physical Society. We are grateful to the members of the organizing committee, whose shared efforts made the meeting in Monterrey fruitful and memorable. Finally, we thank also the speakers and poster presenters for their excellent presentations.

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